

AMICSA 2018

Wednesday 20 June 2018

Radiation Hardened Technologies: (1/3) - IMEC (09:45 - 11:00)

-Conveners: Constantin Papadas

time	[id] title	presenter
09:45	[36] Microchip ATMX150RHA Rad-Hard CMOS 150nm cell-based ASIC family Radiation Characterization Test Report Total Dose (TID) and Single Event Effects (SEE)	Mr LEDUC, eric
10:10	[27] DARE180U platform improvements in release 5.6	Mr FRANCISCATTO, Giancarlo
10:35	[7] The Design Against Radiation Effects (DARE) design platform for TSMC 65nm process.	Mr KAKOULIN, Michael

Radiation Hardened Technologies: (2/3) - IMEC (11:20 - 12:35)

-Conveners: Franco Bigongiari

time	[id] title	presenter
11:20	[48] Overview of ST Space Qualification in 28nm-FDSOI	Dr GASLOT, Gilles
11:45	[34] ATMX150RHA Circuit Design Platform	Mr BERLIVET, Erwann
12:10	[19] DARE SET Simulation Flow Integrated in Virtuoso ADE L/XL Design Environment	Mr VERHAEGEN, Staf

Radiation Hardened Technologies: (3/3) (14:00 - 15:15)

-Conveners: Frank Henkel

time	[id] title	presenter
14:00	[8] ESS180RH: An 180nm digital library addressing Single Event Latch-up based on X-FAB XH018	Mr MITROVGENIS, Dimitris Mr ATHANASSOPOULOS, Theodoros
14:25	[2] Mixed-Signal Test Vehicle in Microchip Atmel ATMX150RHA	Mr FLEURY, Julien
14:50	[21] DARE180U New Analog IPs	Mr BERTI, Laurent